



GL15P06-8

GL Silicon P-Channel Power MOSFET

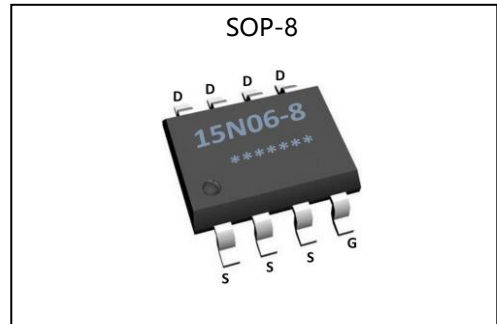
General Description:

The GL15P06-8 uses advanced trench technology and design to provide excellent $R_{DS(ON)}$ with low gate charge. It can be used in a wide variety of applications. The package form is SOP-8, which accords with the RoHS standard.

V_{DSS}	-60	V
I_D	-15	A
P_D	3	W
$R_{DS(ON)type}$	60	m Ω

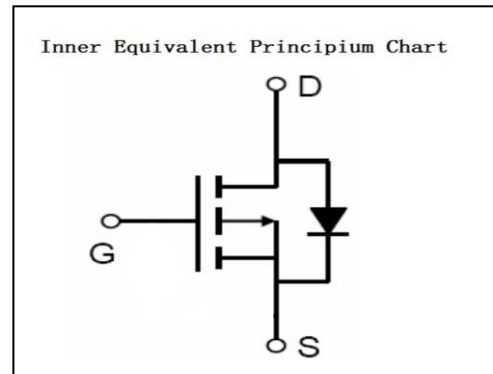
Features:

- $R_{DS(ON)} < 80m\Omega$ @ $V_{GS} = 10V$ (Typ 60m Ω)
- High density cell design for ultra low R_{dson}
- Fully characterized avalanche voltage and current
- Excellent package for good heat dissipation



Applications:

- Power switching application
- Hard switched and high frequency circuits
- Uninterruptible power supply



Absolute (Tc= 25°C unless otherwise specified):

Symbol	Parameter	Rating	Units
V_{DSS}	Drain-to-Source Voltage	-60	V
I_D	Continuous Drain Current	-15	A
I_{DM}	Pulsed Drain Current	-60	A
V_{GS}	Gate-to-Source Voltage	± 20	V
P_D	Power Dissipation	3	W
T_J, T_{stg}	Operating Junction and Storage Temperature Range	150, -55 to 150	$^{\circ}C$



GL15P06-8

GL Silicon P-Channel Power MOSFET

Electrical Characteristics (T_c=25°C unless otherwise specified):

OFF Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
V _{DSS}	Drain to Source Breakdown Voltage	V _{GS} =0V, I _D =250μA	-60	--	--	V
I _{DSS}	Drain to Source Leakage Current	V _{DS} =-60V, V _{GS} = 0V, T _a =25°C	--	--	-1.0	μA
I _{GSS(F)}	Gate to Source Forward Leakage	V _{GS} = +20V	--	--	0.1	μA
I _{GSS(R)}	Gate to Source Reverse Leakage	V _{GS} = -20V	--	--	-0.1	μA

ON Characteristics ^{a3}						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
R _{DS(ON)}	Drain-to-Source On-Resistance	V _{GS} = -10V, I _D = -7.5A	--	60	80	mΩ
V _{GS(TH)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _D =250μA	-1.0	--	-2.5	V

Pulse width tp ≤ 380μs, δ ≤ 2%

Dynamic Characteristics ^{a4}						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
g _{fs}	Forward Transconductance	V _{DS} = -5V, I _D = -7.5A	--	10	--	S
C _{iss}	Input Capacitance	V _{GS} =0V, V _{DS} = -30V f=1.0MHz	--	1100	--	pF
C _{oss}	Output Capacitance		--	95	--	
C _{rss}	Reverse Transfer Capacitance		--	45	--	

Resistive Switching Characteristics ^{a4}						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
t _{d(ON)}	Turn-on Delay Time	V _{DD} = -30V, R _L = -7.5 Ω V _{GS} = -10V, R _G = 3Ω	--	8	--	ns
t _r	Rise Time		--	4	--	
t _{d(OFF)}	Turn-Off Delay Time		--	32	--	
t _f	Fall Time		--	7	--	
Q _g	Total Gate Charge	V _{DD} = -30V, I _D = -4A V _{GS} = -10V	--	35	--	nC
Q _{gs}	Gate to Source Charge		--	5	--	
Q _{gd}	Gate to Drain ("Miller")Charge		--	9	--	



GL15P06-8

GL Silicon P-Channel Power MOSFET

Source-Drain Diode Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
I_S	Continuous Source Current ^{a2} (Body Diode)		--	--	-15	A
V_{SD}	Diode Forward Voltage ^{a3}	$I_S = -15A, V_{GS} = 0V$	--	--	-1.5	V

Symbol	Parameter	Typ.	Units
$R_{\theta JC}$	Junction-to-Case ^{a2}	41.7	°C/W

^{a1}: Repetitive Rating: Pulse width limited by maximum junction temperature.

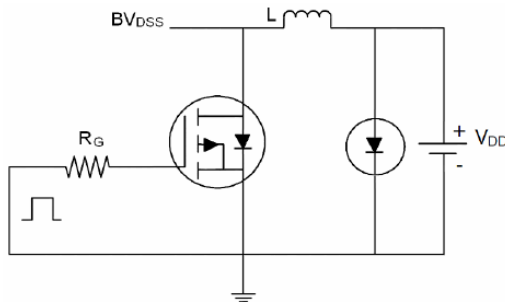
^{a2}: Surface Mounted on FR4 Board, $t \leq 10\text{sec}$.

^{a3}: Pulse Test: Pulse Width $\leq 300\mu\text{s}$, Duty Cycle $\leq 2\%$.

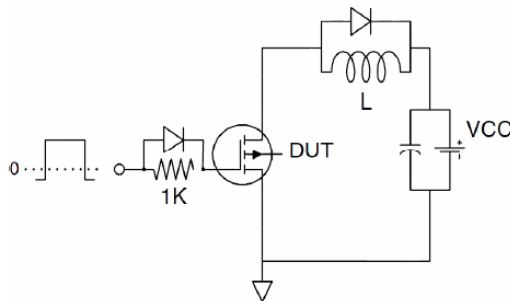
^{a4}: Guaranteed by design, not subject to production

Test circuit

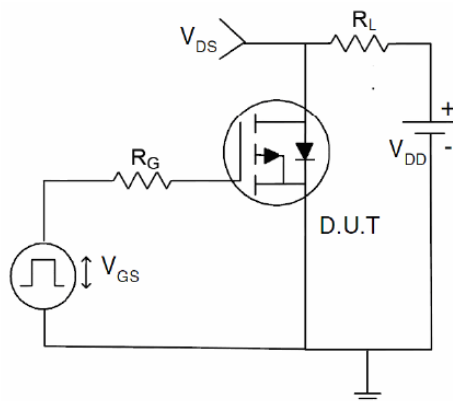
1) E_{AS} Test Circuit



2) Gate Charge Test Circuit



3) Switch Time Test Circuit





GL15P06-8

GL Silicon P-Channel Power MOSFET

Characteristics Curve:

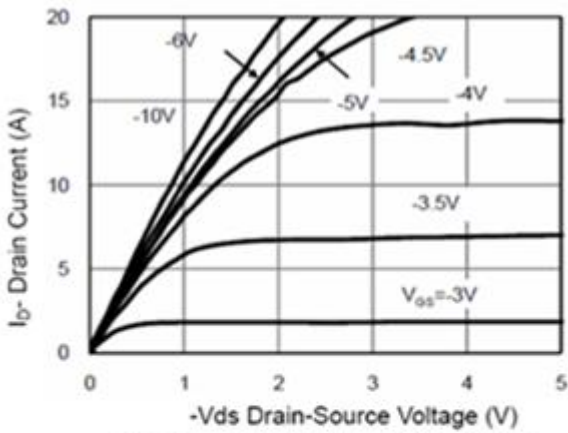


Figure 1 Output Characteristics

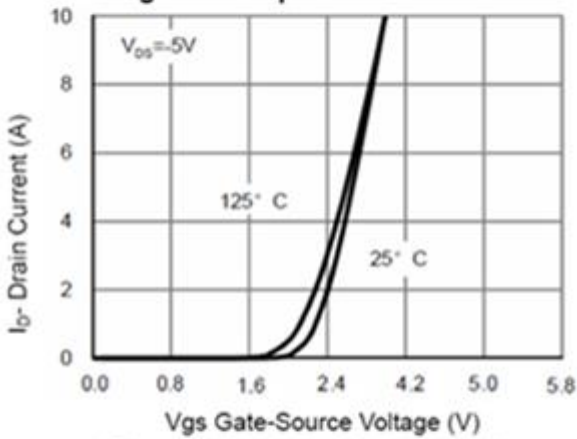


Figure 2 Transfer Characteristics

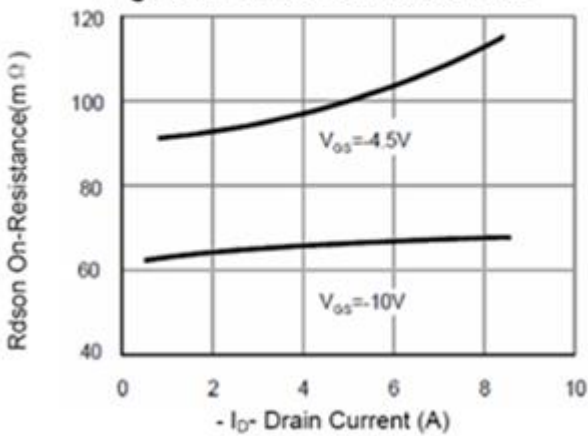


Figure 3 $R_{DS(on)}$ - Drain Current

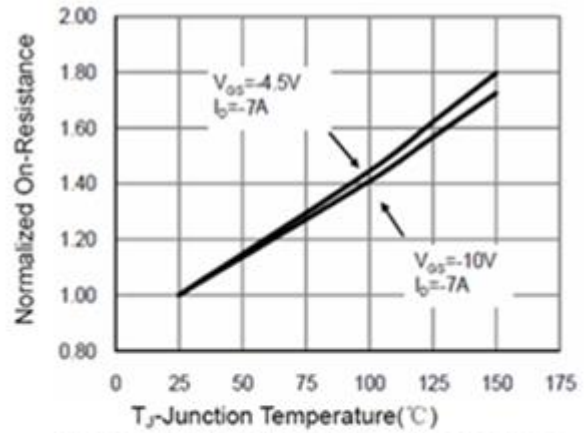


Figure 4 $R_{DS(on)}$ -Junction Temperature

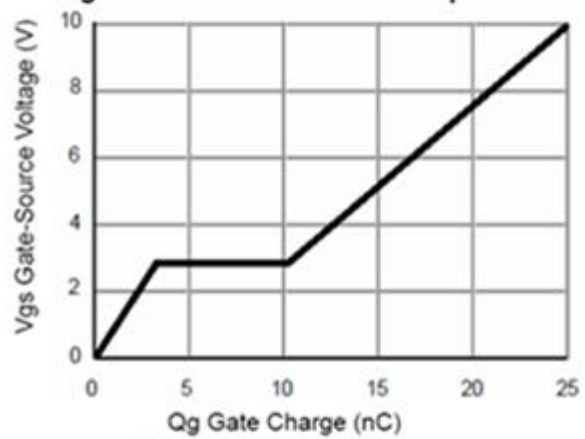


Figure 5 Gate Charge

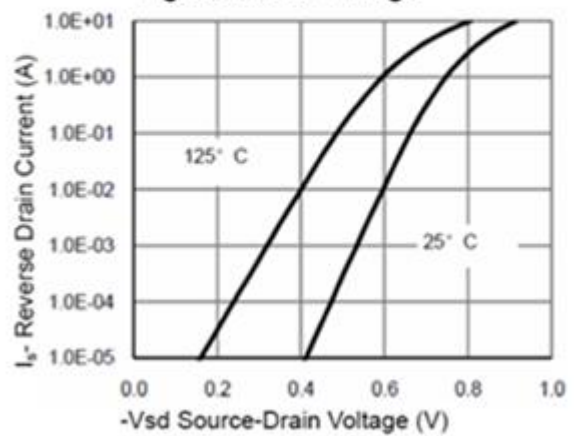


Figure 6 Source- Drain Diode Forward



GL15P06-8

GL Silicon P-Channel Power MOSFET

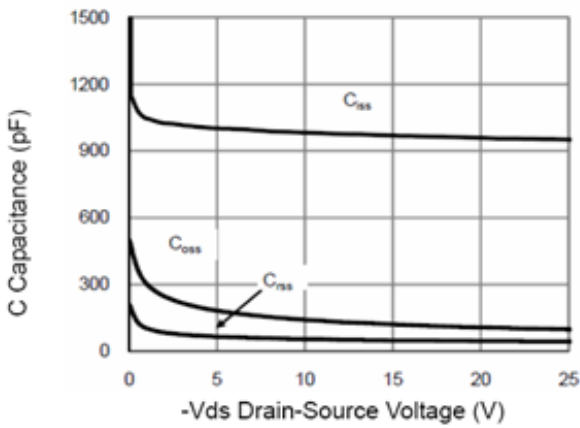


Figure 7 Capacitance vs Vds

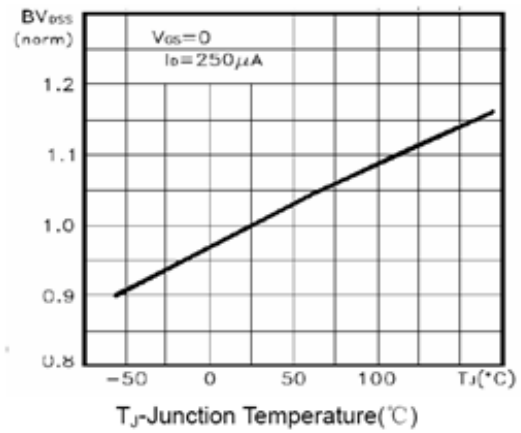


Figure 9 BV_{DSS} vs Junction Temperature

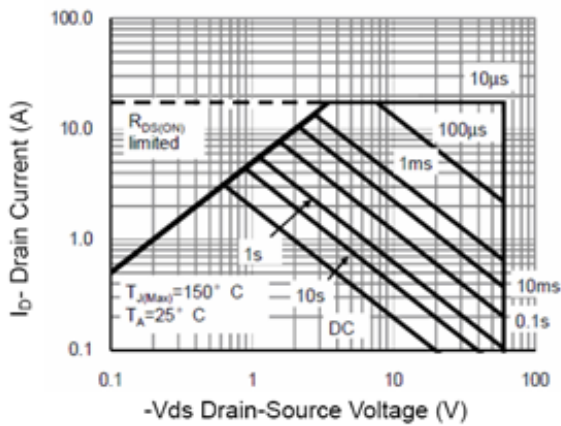


Figure 8 Safe Operation Area

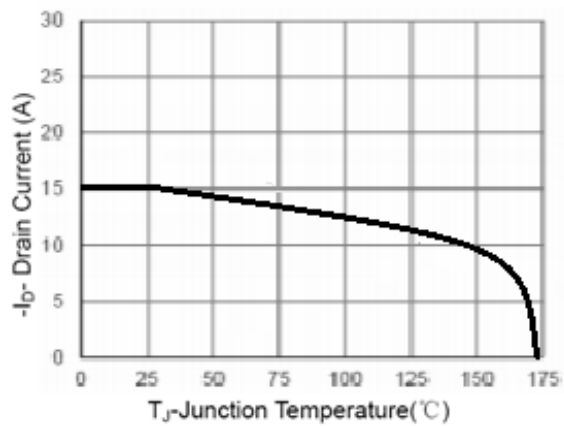


Figure 10 I_D Current De-rating

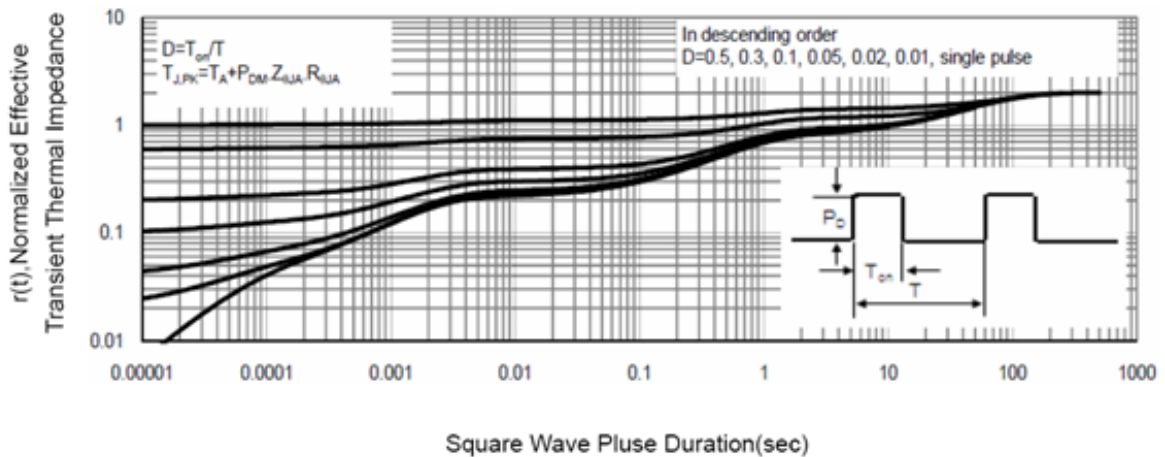


Figure 11 Normalized Maximum Transient Thermal Impedance